

1.	Record Nr.	UNINA990006600550403321
	Autore	Williams, Sharon Anne
	Titolo	The International and National Protection of Movable Cultural Property . A Comparative Study / Sharon A. Williams
	Pubbl/distr/stampa	Dobbs Ferry : Oceana Publ., 1978
	Descrizione fisica	XVIII, 302 p., 22 cm
	Locazione	FSPBC
	Collocazione	III I 14
	Lingua di pubblicazione	Italiano
	Formato	Materiale a stampa
	Livello bibliografico	Monografia
2.	Record Nr.	UNINA9910859501403321
	Autore	Pisano, Raffaele
	Titolo	Homage to Evangelista Torricelli's Opera Geometrica 1644-2024 : text, transcription, commentaries and selected essays as new historical insights / Raffaele Pisano, Jean Dhombres ... [et al.] ; in collaboration with Julie Robarts
	Pubbl/distr/stampa	Switzerland, : Springer, 2024
	ISBN	978-3-031-06962-8
	Descrizione fisica	xvi, 1113 p. : ill. ; 29 cm
	Collana	Logic, epistemology, and the unity of science ; 55
	Altri autori (Persone)	Dhombres, Jean
	Locazione	FI1
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	Lingua di pubblicazione	Inglese
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3. Record Nr.	UNINA9910557701103321
Autore	Zschech Ehrenfried
Titolo	Characterization of Nanomaterials: Selected Papers from 6th Dresden Nanoanalysis Symposiumc
Pubbl/distr/stampa	Basel, Switzerland, : MDPI - Multidisciplinary Digital Publishing Institute, 2021
Descrizione fisica	1 online resource (139 p.)
Soggetti	Technology: general issues
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Sommario/riassunto	This Special Issue "Characterization of Nanomaterials" collects nine selected papers presented at the 6th Dresden Nanoanalysis Symposium, held at Fraunhofer Institute for Ceramic Technologies and Systems in Dresden, Germany, on 31 August 2018. Following the specific motto of this annual symposium "Materials challenges-Micro- and nanoscale characterization", it covered various topics of nanoscale materials characterization along the whole value and innovation chain, from fundamental research up to industrial applications. The scope of this Special Issue is to provide an overview of the current status, recent developments and research activities in the field of nanoscale materials characterization, with a particular emphasis on future scenarios. Primarily, analytical techniques for the characterization of thin films and nanostructures are discussed, including modeling and simulation. We anticipate that this Special Issue will be accessible to a wide audience, as it explores not only methodical aspects of nanoscale materials characterization, but also materials synthesis, fabrication of devices and applications.